

Notice of References Cited	Application/Control No. 10/601,872	Applicant(s)/Patent Under Reexamination CHOI ET AL.	
	Examiner Dah-Wei D. Yuan	Art Unit 1745	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,887,451	05-2005	Dodelet et al.	423/447.3
*	B	US-2004/0167014	08-2004	Yan et al.	502/101
	C	US-			
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	E	US-			
	F	US-			
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	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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